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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	288
Number of Logic Elements/Cells	4608
Total RAM Bits	119808
Number of I/O	142
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2c5q208c8

Each global clock network has a clock control block to select from a number of input clock sources (PLL clock outputs, CLK[] pins, DPCLK[] pins, and internal logic) to drive onto the global clock network. Table 2–2 lists how many PLLs, CLK[] pins, DPCLK[] pins, and global clock networks are available in each Cyclone II device. CLK[] pins are dedicated clock pins and DPCLK[] pins are dual-purpose clock pins.

Table 2–2. Cyclone II Device Clock Resources

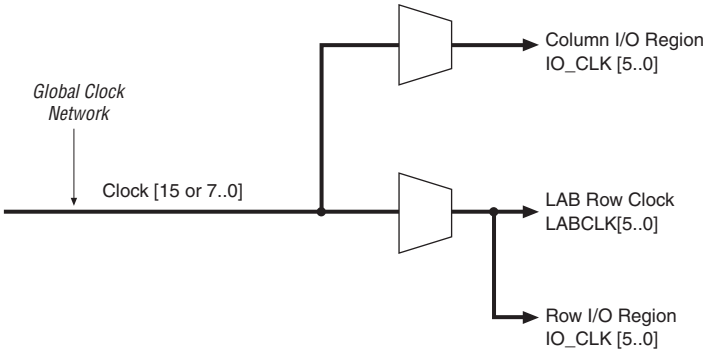
Device	Number of PLLs	Number of CLK Pins	Number of DPCLK Pins	Number of Global Clock Networks
EP2C5	2	8	8	8
EP2C8	2	8	8	8
EP2C15	4	16	20	16
EP2C20	4	16	20	16
EP2C35	4	16	20	16
EP2C50	4	16	20	16
EP2C70	4	16	20	16

Figures 2–11 and 2–12 show the location of the Cyclone II PLLs, CLK[] inputs, DPCLK[] pins, and clock control blocks.

Global Clock Network Distribution

Cyclone II devices contains 16 global clock networks. The device uses multiplexers with these clocks to form six-bit buses to drive column IOE clocks, LAB row clocks, or row IOE clocks (see Figure 2–14). Another multiplexer at the LAB level selects two of the six LAB row clocks to feed the LE registers within the LAB.

Figure 2–14. Global Clock Network Multiplexers



LAB row clocks can feed LEs, M4K memory blocks, and embedded multipliers. The LAB row clocks also extend to the row I/O clock regions.

IOE clocks are associated with row or column block regions. Only six global clock resources feed to these row and column regions. Figure 2–15 shows the I/O clock regions.

Clock Modes

Table 2–8 summarizes the different clock modes supported by the M4K memory.

Table 2–8. M4K Clock Modes

Clock Mode	Description
Independent	In this mode, a separate clock is available for each port (ports A and B). Clock A controls all registers on the port A side, while clock B controls all registers on the port B side.
Input/output	On each of the two ports, A or B, one clock controls all registers for inputs into the memory block: data input, `wren`, and address. The other clock controls the block's data output registers.
Read/write	Up to two clocks are available in this mode. The write clock controls the block's data inputs, `wraddress`, and `wren`. The read clock controls the data output, `rdaddress`, and `rden`.
Single	In this mode, a single clock, together with clock enable, is used to control all registers of the memory block. Asynchronous clear signals for the registers are not supported.

Table 2–9 shows which clock modes are supported by all M4K blocks when configured in the different memory modes.

Table 2–9. Cyclone II M4K Memory Clock Modes

Clocking Modes	True Dual-Port Mode	Simple Dual-Port Mode	Single-Port Mode
Independent	✓		
Input/output	✓	✓	✓
Read/write		✓	
Single clock	✓	✓	✓

M4K Routing Interface

The R4, C4, and direct link interconnects from adjacent LABs drive the M4K block local interconnect. The M4K blocks can communicate with LABs on either the left or right side through these row resources or with LAB columns on either the right or left with the column resources. Up to 16 direct link input connections to the M4K block are possible from the left adjacent LAB and another 16 possible from the right adjacent LAB. M4K block outputs can also connect to left and right LABs through each 16 direct link interconnects. Figure 2–17 shows the M4K block to logic array interface.

There is only one signa and one signb signal for each dedicated multiplier. Therefore, all of the data A inputs feeding the same dedicated multiplier must have the same sign representation. Similarly, all of the data B inputs feeding the same dedicated multiplier must have the same sign representation. The signa and signb signals can be changed dynamically to modify the sign representation of the input operands at run time. The multiplier offers full precision regardless of the sign representation and can be registered using dedicated registers located at the input register stage.

Multiplier Modes

Table 2–12 summarizes the different modes that the embedded multipliers can operate in.

Table 2–12. Embedded Multiplier Modes

Multiplier Mode	Description
18-bit Multiplier	An embedded multiplier can be configured to support a single 18 × 18 multiplier for operand widths up to 18 bits. All 18-bit multiplier inputs and results can be registered independently. The multiplier operands can accept signed integers, unsigned integers, or a combination of both.
9-bit Multiplier	An embedded multiplier can be configured to support two 9 × 9 independent multipliers for operand widths up to 9-bits. Both 9-bit multiplier inputs and results can be registered independently. The multiplier operands can accept signed integers, unsigned integers or a combination of both. There is only one signa signal to control the sign representation of both data A inputs and one signb signal to control the sign representation of both data B inputs of the 9-bit multipliers within the same dedicated multiplier.

Cyclone II devices also use the JTAG port to monitor the logic operation of the device with the SignalTap® II embedded logic analyzer. Cyclone II devices support the JTAG instructions shown in Table 3–1.

Table 3–1. Cyclone II JTAG Instructions (Part 1 of 2)

JTAG Instruction	Instruction Code	Description
SAMPLE/PRELOAD	00 0000 0101	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern to be output at the device pins. Also used by the SignalTap II embedded logic analyzer.
EXTEST *(1)*	00 0000 1111	Allows the external circuitry and board-level interconnects to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
BYPASS	11 1111 1111	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation.
USERCODE	00 0000 0111	Selects the 32-bit USERCODE register and places it between the TDI and TDO pins, allowing the USERCODE to be serially shifted out of TDO.
IDCODE	00 0000 0110	Selects the IDCODE register and places it between TDI and TDO, allowing the IDCODE to be serially shifted out of TDO.
HIGHZ *(1)*	00 0000 1011	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation, while tri-stating all of the I/O pins.
CLAMP *(1)*	00 0000 1010	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation while holding I/O pins to a state defined by the data in the boundary-scan register.
ICR instructions		Used when configuring a Cyclone II device via the JTAG port with a USB Blaster™, ByteBlaster™ II, MasterBlaster™ or ByteBlasterMV™ download cable, or when using a Jam File or JBC File via an embedded processor.
PULSE_NCONFIG	00 0000 0001	Emulates pulsing the nCONFIG pin low to trigger reconfiguration even though the physical pin is unaffected.

SignalTap II Embedded Logic Analyzer

Cyclone II devices support the SignalTap II embedded logic analyzer, which monitors design operation over a period of time through the IEEE Std. 1149.1 (JTAG) circuitry. You can analyze internal logic at speed without bringing internal signals to the I/O pins. This feature is particularly important for advanced packages, such as FineLine BGA® packages, because it can be difficult to add a connection to a pin during the debugging process after a board is designed and manufactured.

For more information on the SignalTap II, see the *Signal Tap* chapter of the *Quartus II Handbook, Volume 3*.

Configuration

The logic, circuitry, and interconnects in the Cyclone II architecture are configured with CMOS SRAM elements. Altera FPGA devices are reconfigurable and every device is tested with a high coverage production test program so you do not have to perform fault testing and can instead focus on simulation and design verification.

Cyclone II devices are configured at system power-up with data stored in an Altera configuration device or provided by a system controller. The Cyclone II device's optimized interface allows the device to act as controller in an active serial configuration scheme with EPCS serial configuration devices. The serial configuration device can be programmed via SRunner, the ByteBlaster II or USB Blaster download cable, the Altera Programming Unit (APU), or third-party programmers.

In addition to EPCS serial configuration devices, Altera offers in-system programmability (ISP)-capable configuration devices that can configure Cyclone II devices via a serial data stream using the Passive serial (PS) configuration mode. The PS interface also enables microprocessors to treat Cyclone II devices as memory and configure them by writing to a virtual memory location, simplifying reconfiguration. After a Cyclone II device has been configured, it can be reconfigured in-circuit by resetting the device and loading new configuration data. Real-time changes can be made during system operation, enabling innovative reconfigurable applications.

Operating Modes

The Cyclone II architecture uses SRAM configuration elements that require configuration data to be loaded each time the circuit powers up. The process of physically loading the SRAM data into the device is called configuration. During initialization, which occurs immediately after configuration, the device resets registers, enables I/O pins, and begins to operate as a logic device. You can use the 10MHz internal oscillator or the optional `CLKUSR` pin during the initialization. The 10 MHz internal oscillator is disabled in user mode. Together, the configuration and initialization processes are called command mode. Normal device operation is called user mode.

If you cannot meet the maximum V_{CC} ramp time requirement, you must use an external component to hold nCONFIG low until the power supplies have reached their minimum recommend operating levels. Otherwise, the device may not properly configure and enter user mode.

Conclusion

Cyclone II devices are hot socketable and support all power-up and power-down sequences with the one requirement that V_{CCIO} and V_{CCINT} be powered up and down within 100 ms of each other to keep the I/O pins from driving out. Cyclone II devices do not require any external devices for hot socketing and power sequencing.

Document Revision History

Table 4–1 shows the revision history for this document.

Table 4–1. Document Revision History

Date & Document Version	Changes Made	Summary of Changes
February 2007 v3.1	• Added document revision history. • Updated "I/O Pins Remain Tri-Stated during Power-Up" section. • Updated "Power-On Reset Circuitry" section. • Added footnote to Figure 4–3.	• Specified V_{CCIO} and V_{CCINT} supplies must be GND when "not powered". • Added clarification about input-tristate behavior. • Added infomation on V_{CC} monotonic ramp.
July 2005 v2.0	Updated technical content throughout.	
February 2005 v1.1	Removed ESD section.	
June 2004 v1.0	Added document to the Cyclone II Device Handbook.	

Table 5–15. Cyclone II Performance (Part 2 of 4)

Applications		Resources Used			Performance (MHz)			
		LEs	M4K Memory Blocks	DSP Blocks	–6 Speed Grade	–7 Speed Grade *(6)*	–7 Speed Grade *(7)*	–8 Speed Grade
Memory M4K block	Simple dual-port RAM 128 × 36 bit *(3)*, *(5)*	0	1	0	235.29	194.93	163.13	163.13
	True dual-port RAM 128 × 18 bit *(3)*, *(5)*	0	1	0	235.29	194.93	163.13	163.13
	FIFO 128 × 16 bit *(5)*	32	1	0	235.29	194.93	163.13	163.13
	Simple dual-port RAM 128 × 36 bit *(4)*,*(5)*	0	1	0	210.08	195.0	163.02	163.02
	True dual-port RAM 128x18 bit *(4)*,*(5)*	0	1	0	163.02	163.02	163.02	163.02
DSP block	9 × 9-bit multiplier *(2)*	0	0	1	260.01	216.73	180.57	180.57
	18 × 18-bit multiplier *(2)*	0	0	1	260.01	216.73	180.57	180.57
	18-bit, 4 tap FIR filter	113	0	8	182.74	147.47	127.74	122.98
Larger Designs	8-bit, 16 tap parallel FIR filter	52	0	4	153.56	131.25	110.44	110.57
	8-bit, 1024 pt, Streaming, 3 Mults/5 Adders FFT function	3191	22	9	235.07	195.0	147.51	163.02
	8-bit, 1024 pt, Streaming, 4 Mults/2 Adders FFT function	3041	22	12	235.07	195.0	146.3	163.02
	8-bit, 1024 pt, Single Output, 1 Parallel FFT Engine, Burst, 3 Mults/5 Adders FFT function	1056	5	3	235.07	195.0	147.84	163.02
	8-bit, 1024 pt, Single Output, 1 Parallel FFT Engine, Burst, 4 Mults/2 Adders FFT function	1006	5	4	235.07	195.0	149.99	163.02
	8-bit, 1024 pt, Single Output, 2 Parallel FFT Engines, Burst, 3 Mults/5 Adders FFT function	1857	10	6	200.0	195.0	149.61	163.02
	8-bit, 1024 pt, Single Output, 2 Parallel FFT Engines, Burst, 4 Mults/2 Adders FFT function	1757	10	8	200.0	195.0	149.34	163.02
	8-bit, 1024 pt, Quad Output, 1 Parallel FFT Engine, Burst, 3 Mults/5 Adders FFT function	2550	10	9	235.07	195.0	148.21	163.02

Table 5–43. Cyclone II I/O Output Delay for Row Pins (Part 4 of 4)

I/O Standard	Drive Strength	Parameter	Fast Corner		–6 Speed Grade	–7 Speed Grade (2)	–7 Speed Grade (3)	–8 Speed Grade	Unit
			Industrial /Auto-motive	Commer-cial					
LVDS	—	t_{OP}	1216	1275	2089	2184	2272	2278	ps
		t_{DIP}	1340	1407	2297	2421	2545	2545	ps
RSDS	—	t_{OP}	1216	1275	2089	2184	2272	2278	ps
		t_{DIP}	1340	1407	2297	2421	2545	2545	ps
MINI_LVDS	—	t_{OP}	1216	1275	2089	2184	2272	2278	ps
		t_{DIP}	1340	1407	2297	2421	2545	2545	ps
PCI	—	t_{OP}	989	1036	2070	2214	2352	2358	ps
		t_{DIP}	1113	1168	2278	2451	2625	2625	ps
PCI-X	—	t_{OP}	989	1036	2070	2214	2352	2358	ps
		t_{DIP}	1113	1168	2278	2451	2625	2625	ps

Notes to Table 5–43:
(1) This is the default setting in the Quartus II software.
(2) These numbers are for commercial devices.
(3) These numbers are for automotive devices.

Maximum Input and Output Clock Rate

Maximum clock toggle rate is defined as the maximum frequency achievable for a clock type signal at an I/O pin. The I/O pin can be a regular I/O pin or a dedicated clock I/O pin.

The maximum clock toggle rate is different from the maximum data bit rate. If the maximum clock toggle rate on a regular I/O pin is 300 MHz, the maximum data bit rate for dual data rate (DDR) could be potentially as high as 600 Mbps on the same I/O pin.

Table 5–44 specifies the maximum input clock toggle rates. Table 5–45 specifies the maximum output clock toggle rates at default load. Table 5–46 specifies the derating factors for the output clock toggle rate for non-default load.

To calculate the output toggle rate for a non-default load, use this formula:

The toggle rate for a non-default load

The loop filter converts these up and down signals to a voltage that is used to bias the VCO. If the charge pump receives a logic high on the up signal, current is driven into the loop filter. If the charge pump receives a logic high on the down signal, current is drawn from the loop filter. The loop filter filters out glitches from the charge pump and prevents voltage over-shoot, which minimizes the jitter on the VCO.

The voltage from the charge pump determines how fast the VCO operates. The VCO is implemented as an four-stage differential ring oscillator. A divide counter, *m*, is inserted in the feedback loop to increase the VCO frequency above the input reference frequency, making the VCO frequency $f_{VCO} = m \times f_{REF}$. Therefore, the feedback clock, f_{FB}, applied to one input of the PFD, is locked to the input reference clock, f_{REF} (f_{IN}/n), applied to the other input of the PFD.

The VCO output can feed up to three post-scale counters (c0, c1, and c2). These post-scale counters allow a number of harmonically related frequencies to be produced by the PLL.

Additionally, Cyclone II PLLs have internal delay elements to compensate for routing on the global clock networks and I/O buffers. These internal delays are fixed and not accessible to the user.

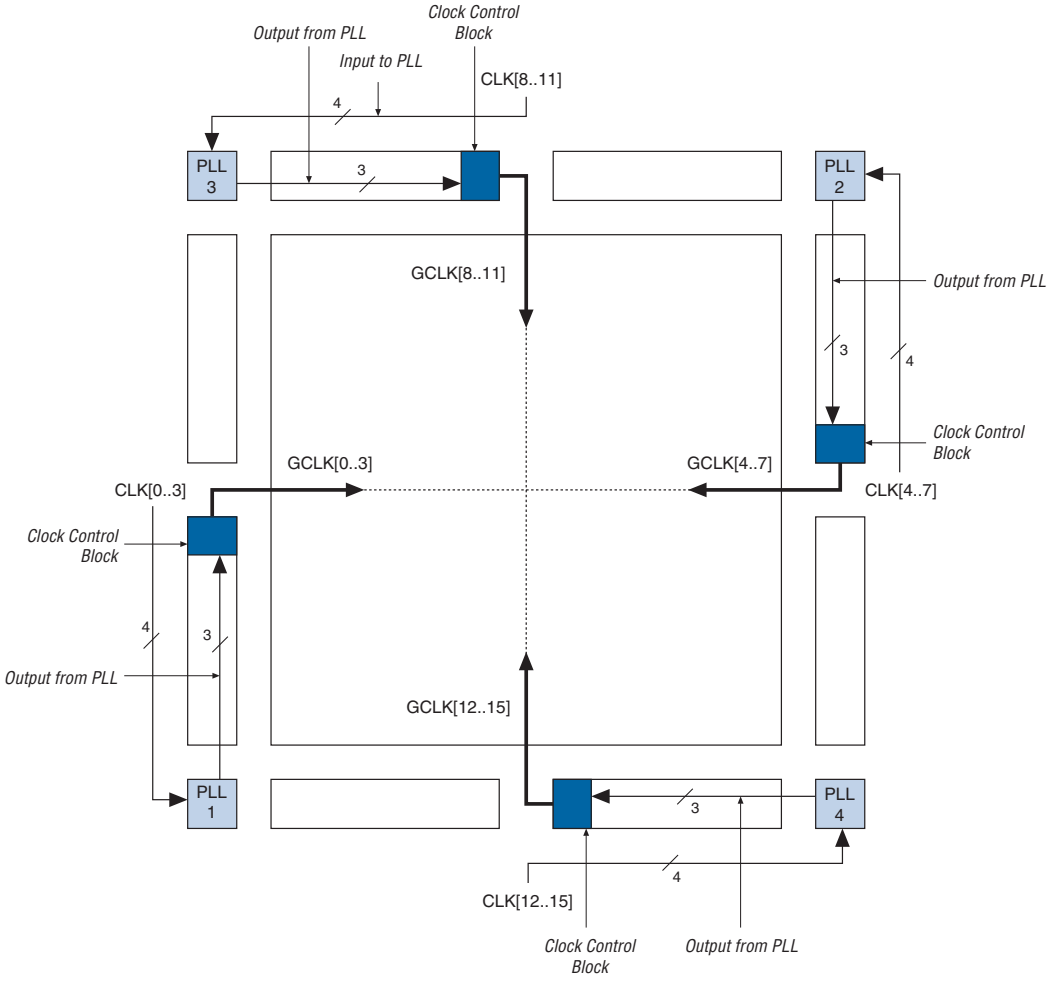
Figure 7–2 shows a simplified block diagram of the major components of a Cyclone II device PLL.

Tables 7–4 and 7–5 describe the Cyclone II PLL input and output ports.

Table 7–4. PLL Input Signals

Port	Description	Source	Destination
inclk[1..0]	Primary and secondary clock inputs to the PLL.	Dedicated clock input pins	*n* counter
pllena	pllena is an active high signal that acts as an enable and reset signal for the PLL. It can be used for enabling or disabling each PLL. When pllena transitions low, the PLL clock output ports are driven to GND and the PLL loses lock. Once pllena transitions high again, the lock process begins and the PLL re-synchronizes to its input reference clock. The pllena port can be driven by an LE output or any general-purpose I/O pin.	Logic array or input pin	PLL control signal
areset	areset is an active high signal that resets all PLL counters to their initial values. When this signal is driven high the PLL resets its counters, clears the PLL outputs and loses lock. Once this signal is driven low again, the lock process begins and the PLL re-synchronizes to its input reference clock. The areset port can be driven by an LE output or any general-purpose I/O pin.	Logic array or input pin	PLL control signal
pfdena	pfdena is an active high signal that enables or disables the up/down output signals from the PFD. When pfdena is driven low, the PFD is disabled, while the VCO continues to operate. The PLL clock outputs continue to toggle regardless of the input clock, but may experience some long-term drift. Because the output clock frequency does not change for some time, you can use the pfdena port as a shutdown or cleanup function when a reliable input clock is no longer available. The pfdena port can be driven by an LE output or any general-purpose I/O pin.	Logic array or input pin	PFD
clkswitch	clkswitch is an active high switchover signal used to initiate manual clock switchover.	Logic array or input pin	PLL control signal

Figure 7–12. Cyclone II Clock Control Blocks Placement



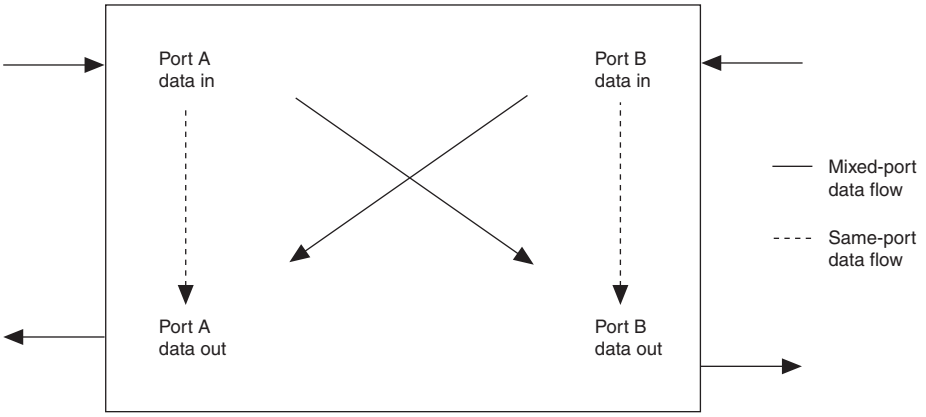
The inputs to the four clock control blocks on each side are chosen from among the following clock sources:

- Four clock input pins
- Three PLL counter outputs
- Two DPCLK pins and two CDPCLK pins from both the left and right sides and four DPCLK pins and two CDPCLK pins from both the top and bottom
- Four signals from internal logic

Read-During-Write Operation at the Same Address

The "Same-Port Read-During-Write Mode" and "Mixed-Port Read-During-Write Mode" sections describe the functionality of the various RAM configurations when reading from an address during a write operation at that same address. There are two read-during-write data flows: same-port and mixed-port. Figure 8–21 shows the difference between these flows.

Figure 8–21. Cyclone II Read-During-Write Data Flow



Same-Port Read-During-Write Mode

For read-during-write operation of a single-port RAM or the same port of a true dual-port RAM, the new data is available on the rising edge of the same clock cycle on which it was written. Figure 8–22 shows a sample functional waveform. When using byte enables in true dual-port RAM mode, the outputs for the masked bytes on the same port are unknown (see Figure 8–2 on page 8–6). The non-masked bytes are read out as shown in Figure 8–22.

You can use any of the user I/O pins for commands and addresses. Because of the symmetrical setup and hold time for the command and address pins at the memory device, you may need to generate these signals from the negative edge of the system clock.

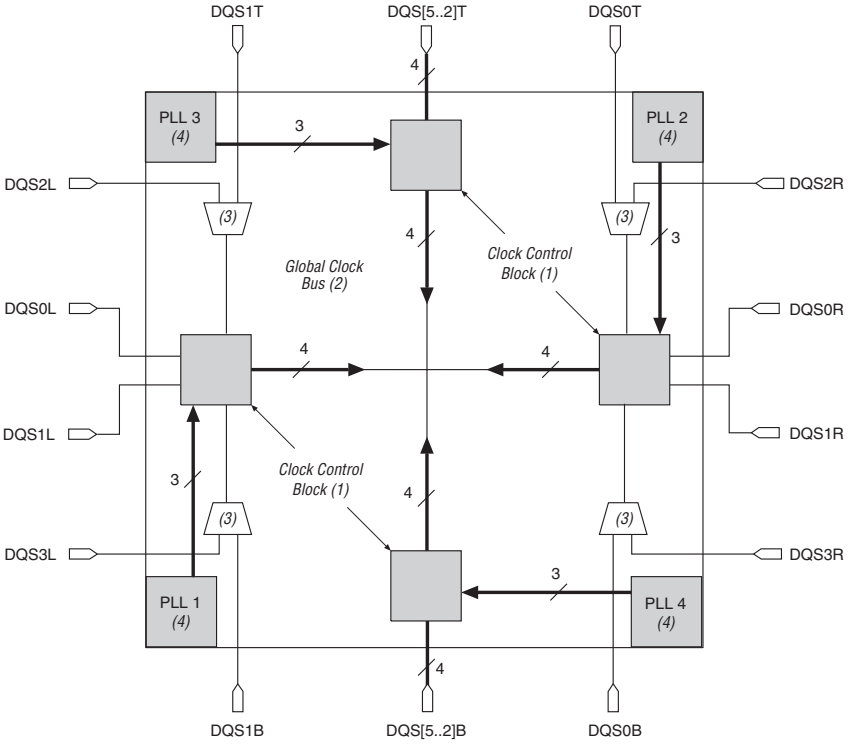
The clocks to the SDRAM device are called CK and CK#. Use any of the user I/O pins via the DDR registers to generate the CK and CK# signals to meet the t_{DQSS} requirements of the DDR SDRAM or DDR2 SDRAM device. The memory device's t_{DQSS} requires the positive edge of the write DQS signal to be within 25% of the positive edge of the DDR SDRAM and DDR2 SDRAM clock input. Because of strict skew requirements between CK and CK# signals, use adjacent pins to generate the clock pair. Surround the pair with buffer pins tied to V_{CC} and pins tied to ground for better noise immunity from other signals.

Read & Write Operation

When reading from the memory, DDR and DDR2 SDRAM devices send the data edge-aligned relative to the data strobe. To properly read the data, the data strobe must be center-aligned relative to the data inside the FPGA. Cyclone II devices feature clock delay control circuitry to shift the data strobe to the middle of the data window. Figure 9–1 shows an example of how the memory sends out the data and data strobe for a burst-of-two operation.

directly to the clock control block. For the larger Cyclone II devices, the corner DQS signals are multiplexed before they are routed to the clock control block. When you use the corner DQS pins for DDR implementation, there is a degradation in the performance of the memory interface. The clock control block is used to select from a number of input clock sources, in this case either PLL clock outputs or DQS pins, to drive onto the global clock bus. Figure 9–7 shows the corner DQS signal mappings for EP2C15 through EP2C70 devices.

Figure 9–7. Corner DQS Signal Mapping for EP2C15–EP2C70 Devices



Notes to Figure 9–7:

(1) There are four control blocks on each side.
(2) There are a total of 16 global clocks available.
(3) Only one of the corner DQS pins in each corner can feed the clock control block at a time. The other DQS pins can be used as general purpose I/O pins.
(4) PLL resource can be lost if all DQS pins from one side are used at the same time.
(5) Top/bottom and side IOE have different timing.

When the `signa` and `signb` signals are unused, the Quartus® II software sets the multiplier to perform unsigned multiplication by default.

Output Registers

You can choose to register the embedded multiplier output using the output registers in 18- or 36-bit sections depending on the operational mode of the multiplier. The following control signals are available to each output register within the embedded multiplier:

- clock
- clock enable
- asynchronous clear

All input and output registers within a single embedded multiplier are fed by the same clock, clock enable, or asynchronous clear signal.

See the *Cyclone II Architecture* chapter in Volume 1 of the ***Cyclone II Device Handbook*** for more information on the embedded multiplier routing and interface.

Operational Modes

The embedded multiplier can be used in one of two operational modes, depending on the application needs:

- One 18-bit multiplier
- Up to two 9-bit independent multipliers

The Quartus II software includes megafunctions used to control the mode of operation of the multipliers. After you have made the appropriate parameter settings using the megafunction's MegaWizard® Plug-In Manager, the Quartus II software automatically configures the embedded multiplier.

The Cyclone II embedded multipliers can also be used to implement multiplier adder and multiplier accumulator functions where the multiplier portion of the function is implemented using embedded multipliers and the adder or accumulator function is implemented in logic elements (LEs).

For more information on megafunction and Quartus II support for Cyclone II embedded multipliers, see the "Software Support" section.

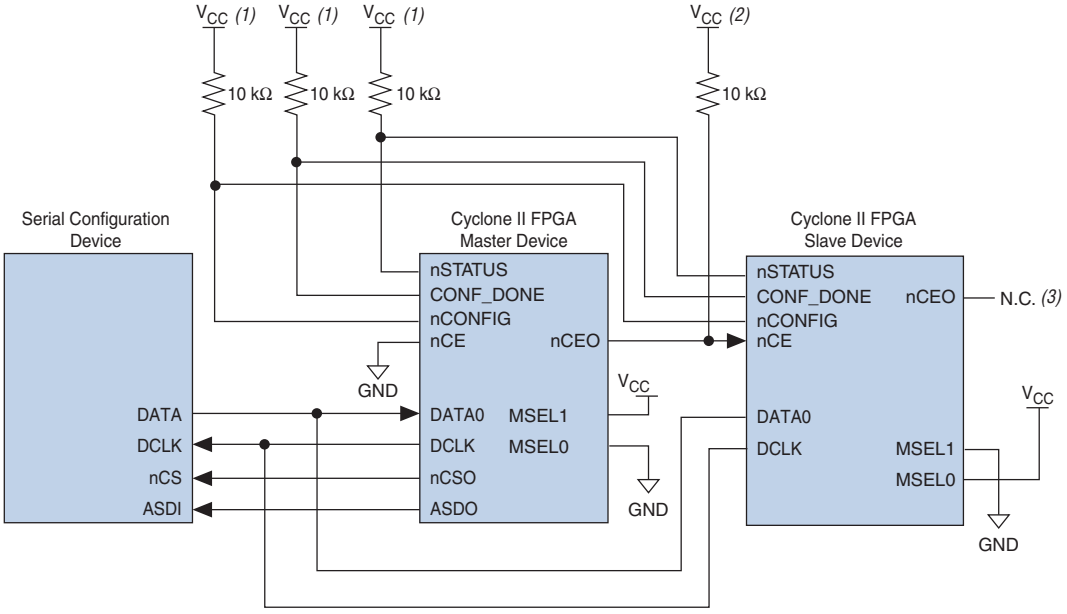
Document Revision History

Table 12–4 shows the revision history for this document.

Table 12–4. Document Revision History

Date & Document Version	Changes Made	Summary of Changes
February 2007 v1.2	• Added document revision history. • Updated "Software Support" section.	• Removed reference to third-party synthesis tool: LeonardoSpectrum and Synplify.
November 2005 v2.1	Updated Introduction.	
June 2004 v1.0	Added document to the Cyclone II Device Handbook.	

Figure 13–4. Multiple Device AS Configuration



Notes to Figure 13–4:

(1) Connect the pull-up resistors to a 3.3-V supply.

(2) Connect the pull-up resistor to the V_{CCIO} supply voltage of I/O bank that the nCEO pin resides in.

(3) The nCEO pin can be left unconnected or used as a user I/O pin when it does not feed another device's nCE pin.

As shown in Figure 13–4, the nSTATUS and CONF_DONE pins on all target FPGAs are connected together with external pull-up resistors. These pins are open-drain bidirectional pins on the FPGAs. When the first device asserts nCEO (after receiving all of its configuration data), it releases its CONF_DONE pin. However, the subsequent devices in the chain keep the CONF_DONE signal low until they receive their configuration data. When all the target FPGAs in the chain have received their configuration data and have released CONF_DONE, the pull-up resistor pulls this signal high, and all devices simultaneously enter initialization mode.

For more information on how to use the USB-Blaster, MasterBlaster, ByteBlaster II or ByteBlasterMV cables, refer to the following documents:

- *USB-Blaster USB Port Download Cable Data Sheet*
- *MasterBlaster Serial/USB Communications Cable Data Sheet*
- *ByteBlaster II Parallel Port Download Cable Data Sheet*
- *ByteBlasterMV Parallel Port Download Cable Data Sheet*

JTAG Configuration

The Joint Test Action Group (JTAG) has developed a specification for boundary-scan testing. This boundary-scan test (BST) architecture allows you to test components on PCBs with tight lead spacing. The BST architecture can test pin connections without using physical test probes and capture functional data while a device is operating normally. The JTAG circuitry can also be used to shift configuration data into the device. The Quartus II software automatically generates SOF files that can be used for JTAG configuration with a download cable in the Quartus II programmer.

For more information on JTAG boundary-scan testing, see the following documents:

- *IEEE 1149.1 (JTAG) Boundary-Scan Testing for Cyclone II Devices* chapter in Volume 2 of the *Cyclone II Device Handbook*
- Jam Programming & Testing Language Specification

Cyclone II devices are designed such that JTAG instructions have precedence over any device configuration modes. This means that JTAG configuration can take place without waiting for other configuration modes to complete. For example, if you attempt JTAG configuration of Cyclone II devices during PS configuration, PS configuration terminates and JTAG configuration begins. If the Cyclone II `MSEL` pins are set to AS or fast AS mode, the Cyclone II device does not output a `DCLK` signal when JTAG configuration takes place.

You cannot use the Cyclone II decompression feature if you are configuring your Cyclone II device when using JTAG-based configuration.

operate the TAP controller, and the TDI and TDO pins provide the serial path for the data registers. The TDI pin also provides data to the instruction register, which then generates control logic for the data registers.

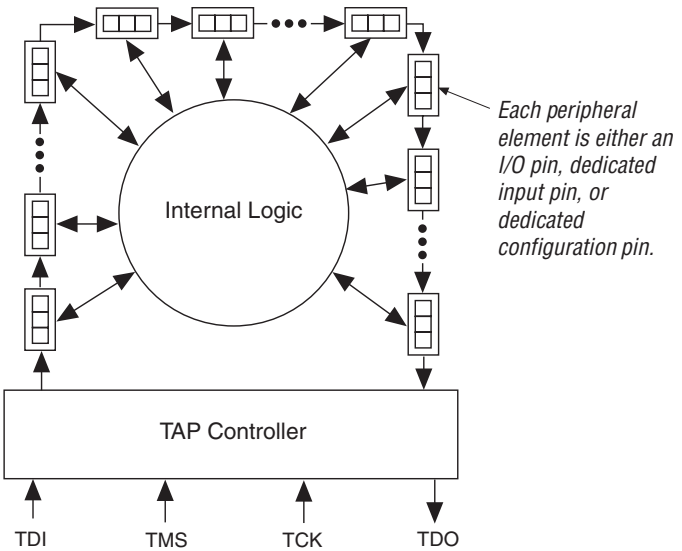
IEEE Std. 1149.1 Boundary-Scan Register

The boundary-scan register is a large serial shift register that uses the TDI pin as an input and the TDO pin as an output. The boundary-scan register consists of 3-bit peripheral elements that are associated with Cyclone II I/O pins. You can use the boundary-scan register to test external pin connections or to capture internal data.

See the *Configuration & Testing* chapter in Volume 1 of the *Cyclone II Device Handbook* for the Cyclone II device boundary-scan register lengths.

Figure 14–3 shows how test data is serially shifted around the periphery of the IEEE Std. 1149.1 device.

Figure 14–3. Boundary-Scan Register



Boundary-Scan Cells of a Cyclone II Device I/O Pin

The Cyclone II device 3-bit boundary-scan cell (BSC) consists of a set of capture registers and a set of update registers. The capture registers can connect to internal device data via the OUTJ and OEJ signals, and connect